

Notice of References Cited	Application/Control No. 09/706,274	Applicant(s)/Patent Under Reexamination ARNEY ET AL.	
	Examiner Arlen Soderquist	Art Unit 1743	Page 2 of 2

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Gabriel, C. et al, Chemical Abstracts 1995, 122, abstract 175490z.
	V	Fabianowski, W. et al, Advanced Materials for Optics and Electronics 1995, 5, 199-213.
	W	Ziaie, B. et al, Journal of Microelectromechanical Systems 1996, 5, 166-179.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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